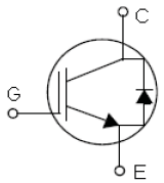
Dec 2013

SemiHow
Know-How for Semiconductor

HIH30N60BP
600V PT IGBT

V_{CES} = 600 V
I_C = 30 A
$V_{CE(sat)\ typ}$ = 2.2 V

TO-3P



FEATURES

- Low $V_{CE(sat)}$
- Maximum Junction Temperature 150℃
- Short Circuit Withstand Time 5μs
- Designed for Operation Between 1-20KHz
- Very tight Parameter Distribution
- High Ruggedness, Temperature stable behavior

Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V_{CES}	Collector-Emitter Voltage	600	V
I_C	Collector Current – Continuous (T_C = 25℃)	60	A
	Collector Current – Continuous (T_C = 100℃)	30	A
I_{CM}	Collector Current – Pulsed (Note 1)	90	A
I_F	Diode Forward Current – Continuous (T_C = 25℃)	60	A
	Diode Forward Current – Continuous (T_C = 100℃)	30	A
I_{FM}	Diode Current – Pulsed (Note 1)	90	A
V_{GES}	Gate-Emitter Voltage	±20	V
t_{SC}	Short circuit withstand time (V_{GE}=15V, V_{CC}=400V, T_C=150℃)	5	μA
P_D	Power Dissipation (T_C = 25℃)	208	W
T_J	Operating Temperature Range	-40 to +150	℃
T_{STG}	Storage Temperature Range	-55 to +150	℃
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	260	℃

Notes.
1. Pulse width limited by max junction temperature

Thermal Resistance Characteristics

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$(IGBT)	Junction-to-Case	--	0.6	℃/W
$R_{\theta JC}$(Diode)	Junction-to-Case	--	0.9	
$R_{\theta JA}$	Junction-to-Ambient	--	40	

Package Marking and Odering Information

Device Marking	Week Marking	Package	Packing	Quantity	RoHS Status
HIH30N60BP	YWWX	TO-3P	Tube	30	Pb Free
HIH30N60BP	YWWXg	TO-3P	Tube	30	Halogen Free

Electrical Characteristics of the IGBT T_C=25 °C unless otherwise specified

Symbol	Parameter	Test Conditions		Min	Typ	Max	Units
On Characteristics							
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	V_{CE} = V_{GE}, I_C = 1.2 mA		4.4	5.7	6.6	V
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	V_{GE} = 15 V, I_C = 30 A	T_C = 25℃	--	2.2	2.6	V
			T_C = 125℃	--	2.2	2.7	
Off Characteristics							
BV_{CES}	Collector-Emitter Breakdown Voltage	V_{GE} = 0 V, I_C = 1 mA		600	--	--	V
I_{CES}	Zero Gate Voltage Collector Current	V_{CE} = 600 V, V_{GE} = 0 V		--	--	100	μA
I_{GES}	Gate-Emitter Leakage Current	V_{GE} = ±20 V, V_{CE} = 0 V		--	--	±100	nA
Dynamic Characteristics							
C_{iss}	Input Capacitance	V_{CE} = 25 V, V_{GE} = 0 V, f = 1.0 MHz		--	1044	--	pF
C_{oss}	Output Capacitance			--	143	--	pF
C_{rss}	Reverse Transfer Capacitance			--	53	--	pF
Switching Characteristics							
$t_{d(on)}$	Turn-On Time	V_{CC} = 300 V, I_C = 30 A, R_G = 20 Ω, V_{GE} = -10/15V Inductive load, T_C = 25℃		--	57	--	ns
t_r	Turn-On Rise Time			--	81	--	ns
$t_{d(off)}$	Turn-Off Delay Time			--	139	--	ns
t_f	Turn-Off Fall Time			--	152	--	ns
E_{on}	Turn-On Switching Loss			--	0.87	--	mJ
E_{off}	Turn-Off Switching Loss			--	1.02	--	mJ
E_{ts}	Total Switching Loss			--	1.89	--	mJ
$t_{d(on)}$	Turn-On Time	V_{CC} = 300 V, I_C = 30 A, R_G = 20 Ω, V_{GE} = -10/15V Inductive load, T_C = 125℃		--	52	--	ns
t_r	Turn-On Rise Time			--	86	--	ns
$t_{d(off)}$	Turn-Off Delay Time			--	148	--	ns
t_f	Turn-Off Fall Time			--	334	--	ns
E_{on}	Turn-On Switching Loss			--	1.02	--	mJ
E_{off}	Turn-Off Switching Loss			--	1.72	--	mJ
E_{ts}	Total Switching Loss			--	2.74	--	mJ
Q_g	Total Gate Charge	V_{CC} = 480V, I_C = 30 A, V_{GE} = 15 V		--	104	--	nC
L_E	Internal Emitter Inductance			--	13	--	nH
$I_{C(SC)}$	Short Circuit Collector Current	V_{CC} = 400 V, t_{SC} ≤ 5s, V_{GE} = 15V, T_C = 25℃		--	180	--	A

Electrical Characteristics of the Diode

V_{FM}	Diode Forward Voltage	I_F = 30 A, V_{GE} = 0 V	T_C = 25℃	--	2.3	--	V
			T_C = 125℃	--	1.9	--	
t_{rr}	Diode Reverse Recovery Time	I_F = 30 A, V_R = 300 V di_F/dt = 200 A/μs, T_C = 25℃		--	167	--	ns
I_{rr}	Diode Peak Reverse Recovery Current			--	15	--	A
Q_{rr}	Diode Reverse Recovery Charge			--	0.88	--	μC
di_{rr}/dt	Diode Peak rate of fall of Reverse Recovery Current during t_b			--	96	--	A/μs
E_{rec}	Diode Reverse Recovery Energy			--	0.17	--	mJ
t_{rr}	Diode Reverse Recovery Time	I_F = 30 A, V_R = 300 V di_F/dt = 200 A/μs, T_C = 125℃		--	335	--	ns
I_{rr}	Diode Peak Reverse Recovery Current			--	30	--	A
Q_{rr}	Diode Reverse Recovery Charge			--	1.43	--	μC
di_{rr}/dt	Diode Peak rate of fall of Reverse Recovery Current during t_b			--	90	--	A/μs
E_{rec}	Diode Reverse Recovery Energy			--	0.35	--	mJ

Typical Characteristics

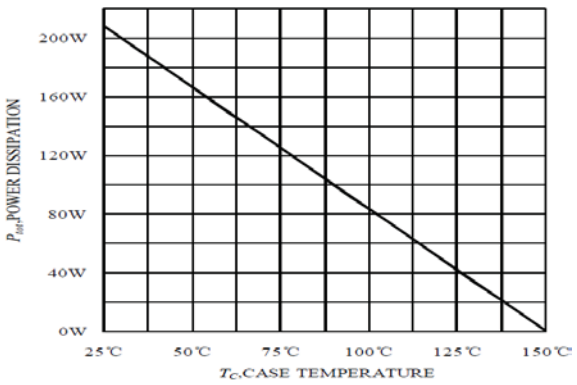


Figure 1. Power dissipation as a function of case temperature(T_j≤150℃)

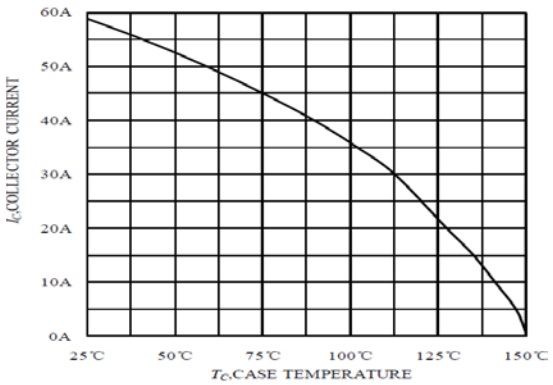


Figure 2. Collector current as a function of case temperature(V_{GE}≥15V， T_j ≤150℃)

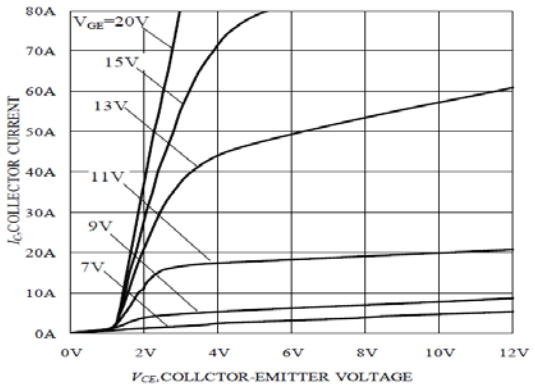


Figure 3. Typical output characteristic (T_j=25℃)

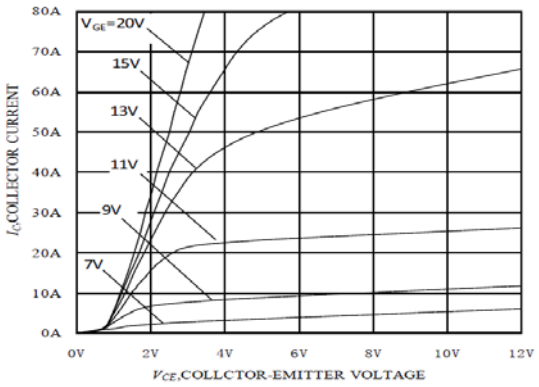


Figure 4. Typical output characteristic (T_j=125℃)

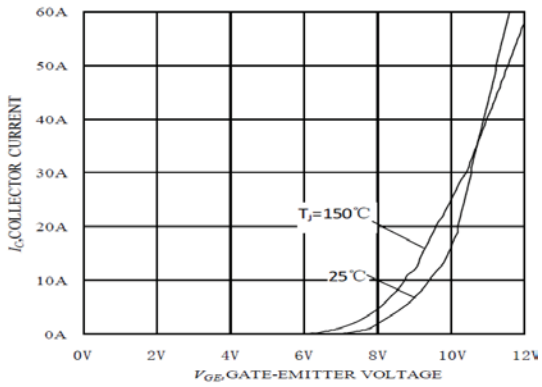


Figure 5. Typical transfer characteristic (V_{CE}=20V)

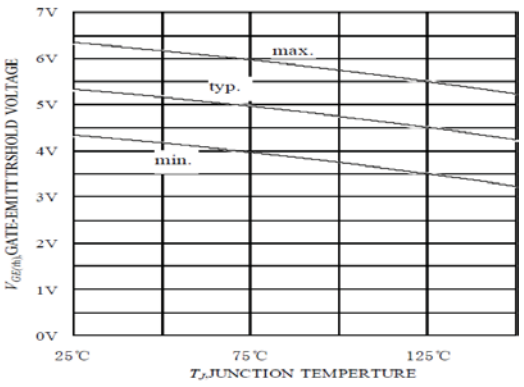


Figure 6. Gate-emitter threshold voltage as a function of junction temperature (I_C=1.2mA)

Typical Characteristics

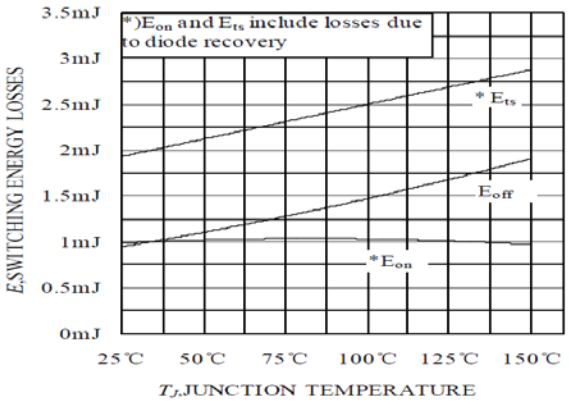


Figure9. Typical switching energy losses as a function of Junction temperature (inductive load, T_j=150℃, V_{CE}=300V, V_{GE}=-10/15V, R_G=20Ω)

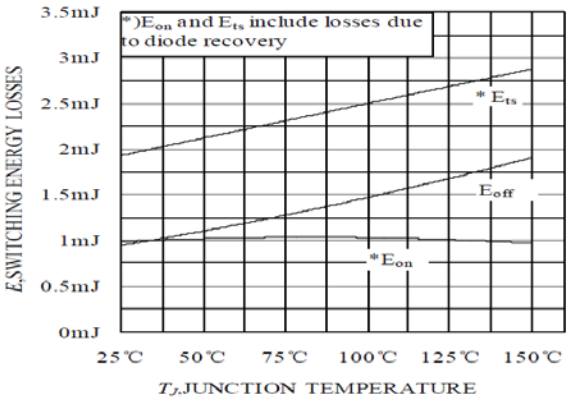


Figure9. Typical switching energy losses as a function of Junction temperature (inductive load, T_j=150℃, V_{CE}=300V, V_{GE}=-10/15V, R_G=20Ω)

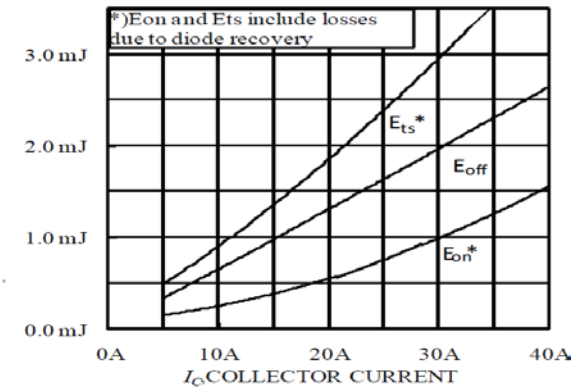


Figure 8. Typical switching energy losses as a function of collector current (inductive load, T_j=150℃, V_{CE}=300V, V_{GE}=-10/15V, R_G=20Ω)

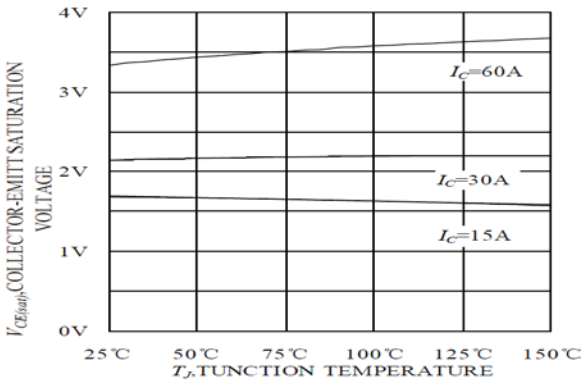


Figure 10. Typical collector-emitter saturation voltage as a function of junction temperature (V_{GE}=15V)

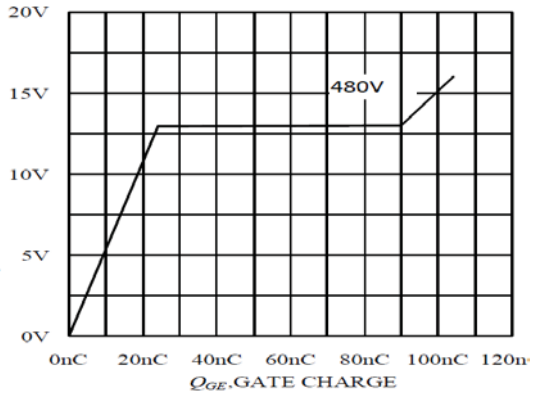


Figure 11. Gate charge (I_C=30A)

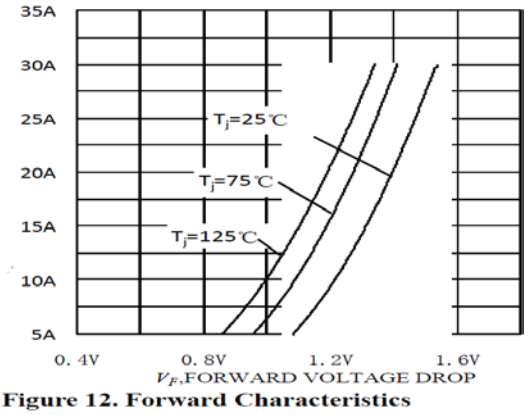


Figure 12. Forward Characteristics

Typical Characteristics

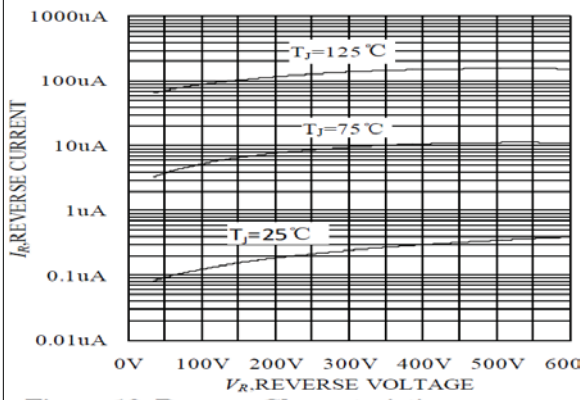


Figure 13. Reverse Characteristic

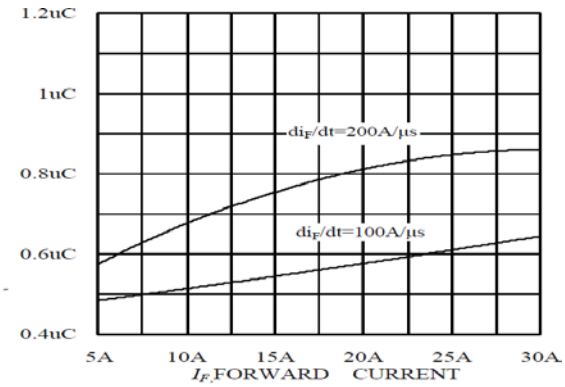


Figure 14. Stored Charge

Package Dimension

TO-3P